

Europe TC Chapter Compound Semiconductor Materials Global Technical Committee

Liaison Report

November 17, 2021

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Meeting Information

- Last meeting
 - November 17, 2021
 - Online via Official Virtual TC Chapter Meeting
 - 11:00 AM – 1:00 PM CET
- Next meeting
 - May, 2022
 - Exact date and time will be determined.

<http://www.semi.org/en/standards-events>

Leadership

- Co-Chair: Arnd Weber (SiCrystal)

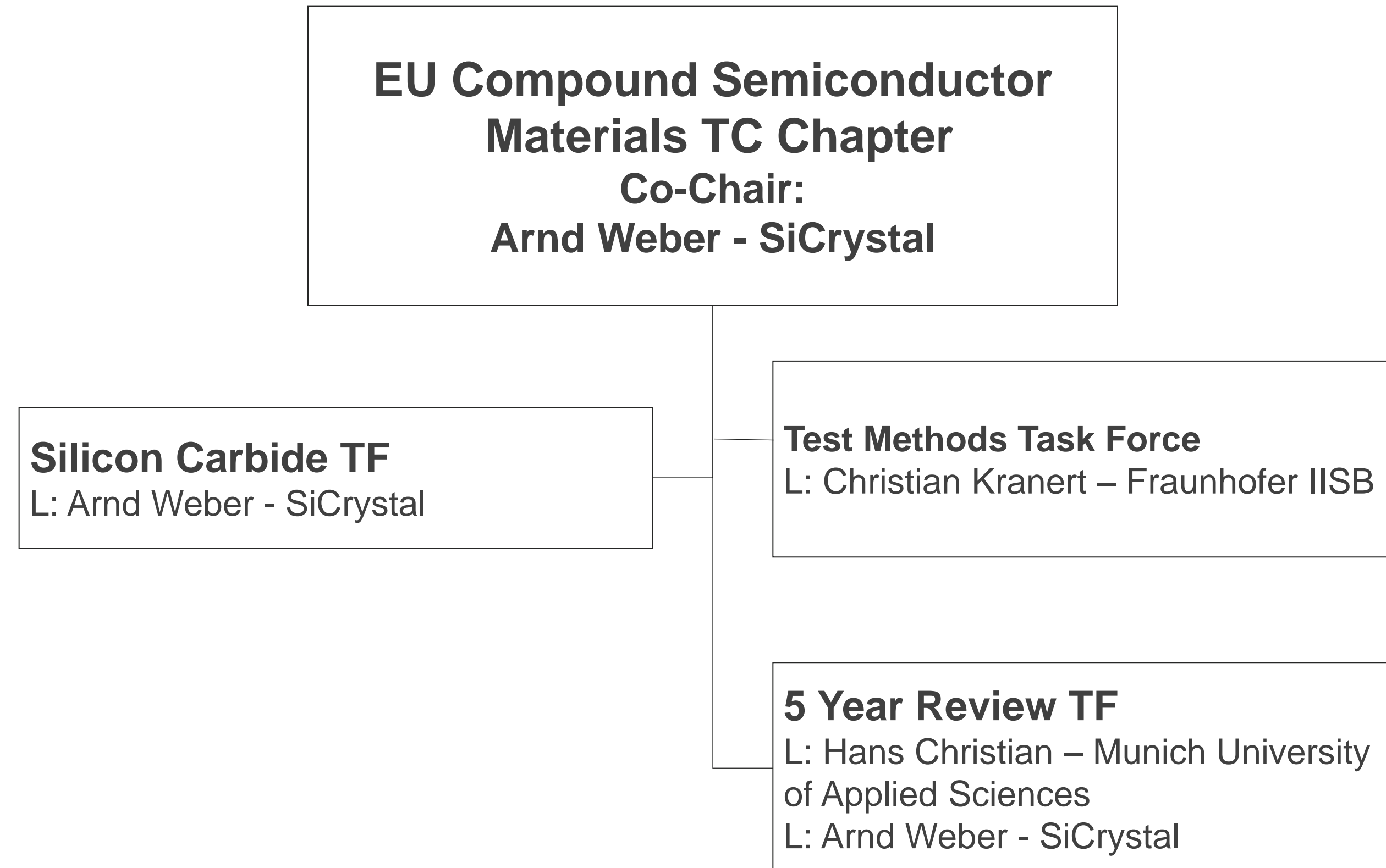


- 2nd Co-Chair position currently open

TFOF Changes

- TFOF Revision
 - From: Full-Wafer TSD Density Mapping of 4H-SiC Task Force
 - To: Test Methods Task Force

Organization Chart



Ballot Result

Doc #	Title	Committee Action
6717	New Standard: Test Method For Determination Of Threading Screw Dislocation Density In 4H-SIC By X-Ray Topography	Passed with editorial changes

Authorized Activity

Doc #	Type	SC/TF/WG	Details
6870	SNARF	Test Methods Task Force	New Standard: Test Method for Quantifying Basal Plane Dislocations in 4H-SiC by X-ray Topography

Task Force Highlights [1/2]



- SiC TF
 - Leader: Arnd Weber (SiCrystal)
 - Doc. 6615, Revision of M55-0817 Specification for Polished Monocrystalline Silicon Carbide Wafers
 - To include 200 mm wafer for Silicon Carbide
 - Ballot passed and forwarded to ISC A&R
 - Document is published as SEMI M55-0921
- Full-Wafer TSD Density Mapping of 4H-SiC TF
 - Leader: Christian Kranert (Fraunhofer)
 - TF name was revised to Test Methods TF.
 - 6716, New Standard: Test Method for Quantifying Threading Screw Dislocations (TSDs) in 4H-SiC Crystals
 - Passed, forwarding to ISC for procedural review.

Task Force Highlights [2/2]



- 5 Year Review TF
 - Leaders
 - Hans Christian – Munich University of Applied Sciences
 - Arnd Weber (SiCrystal)
 - Reviewing Standards due for 5 year review
 - SEMI M46 - Test Method for Measuring Carrier Concentrations in Epitaxial Layer Structures by ECV Profiling
 - Needs experts to review
 - SEMI M63 - Test Method for Measuring the Al Fraction in AlGaAs on GaAs Substrates by High Resolution X-Ray Diffraction
 - Needs experts to review
 - SEMI M75 - Specification for Polished Monocrystalline Gallium Antimonide Wafers
 - Needs experts to review

Thank you!

Staff Contact: Kevin Nguyen, SEMI HQ
• knguyen@semi.org
